

TOSHIBA TRANSISTOR SILICON PNP EPITAXIAL TYPE (PCT PROCESS)

2SA1300

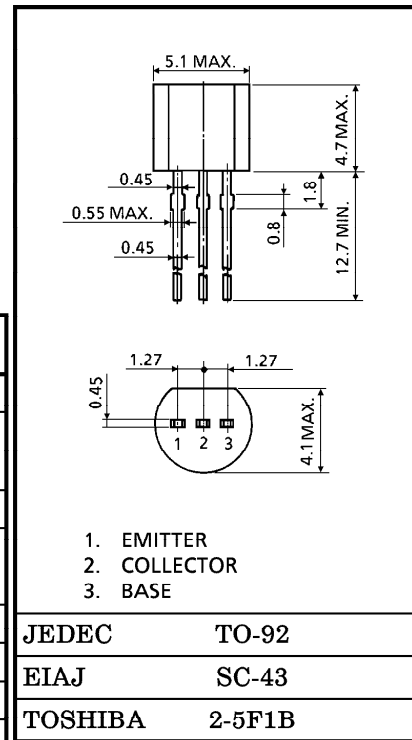
Unit in mm

STROBO FLASH APPLICATIONS
MEDIUM POWER AMPLIFIER APPLICATIONS

- High DC Current Gain and Excellent h_{FE} Linearity
 : $h_{FE}(1) = 140 \sim 600$ ($V_{CE} = -1V, I_C = -0.5A$)
 : $h_{FE}(2) = 60$ (Min.), 120 (Typ.) ($V_{CE} = -1V, I_C = -4A$)
- Low Saturation Voltage
 : $V_{CE(sat)} = -0.5V$ (Max.) ($I_C = -2A, I_B = -50mA$)

MAXIMUM RATINGS ($T_a = 25^\circ C$)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Collector-Base Voltage		V_{CBO}	-20	V
Collector-Emitter Voltage		V_{CES}	-20	V
		V_{CEO}	-10	
Emitter-Base Voltage		V_{EBO}	-6	V
Collector Current	DC	I_C	-2	mA
	Pulsed (Note 1)	I_{CP}	-5	
Base Current		I_B	-2	mA
Collector Power Dissipation		P_C	750	mW
Junction Temperature		T_j	150	$^\circ C$
Storage Temperature Range		T_{stg}	-55~150	$^\circ C$



Note 1 : Pulse Width = 10ms (Max.), Duty Cycle = 30% (Max.)

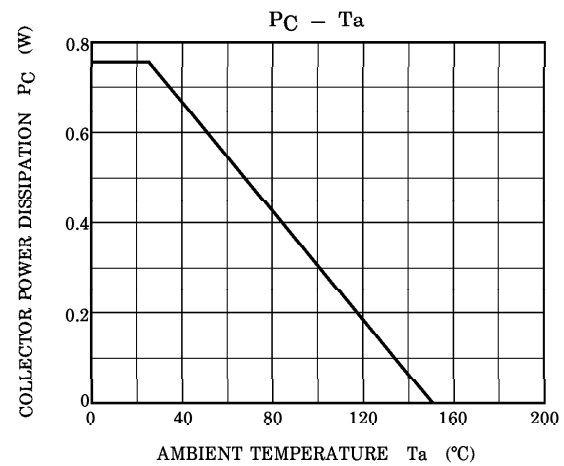
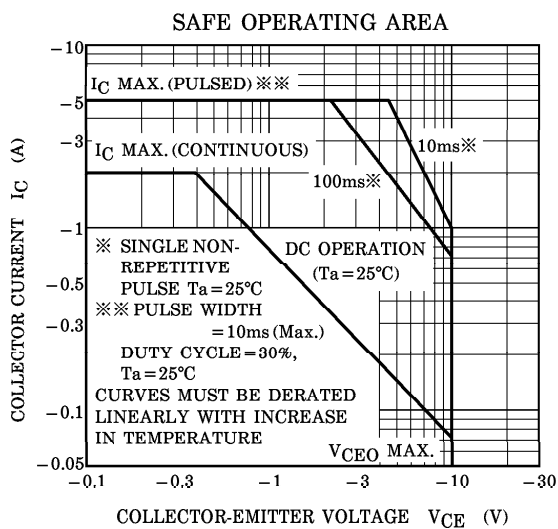
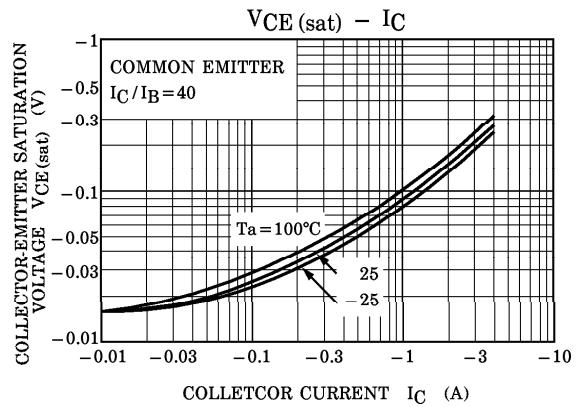
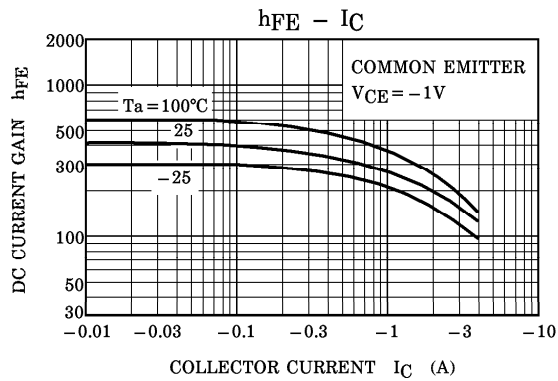
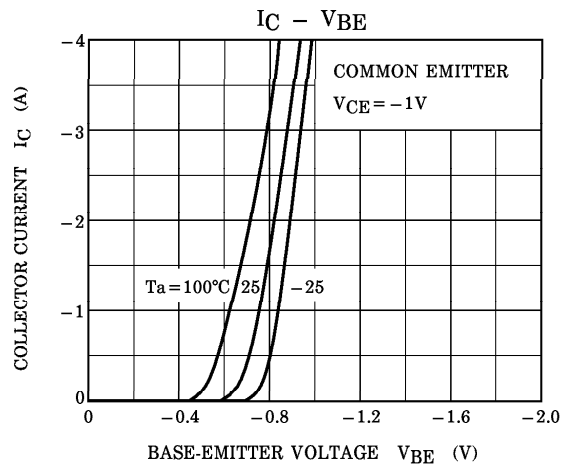
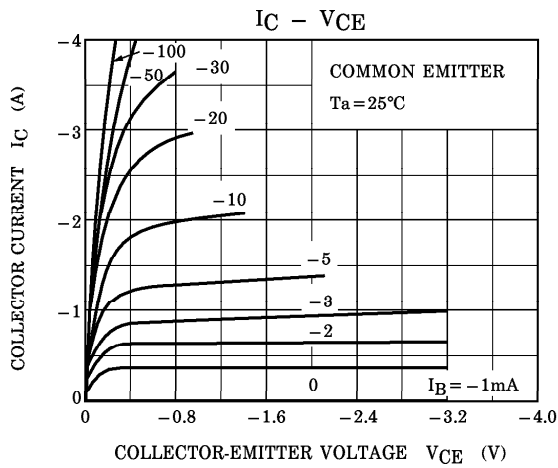
ELECTRICAL CHARACTERISTICS ($T_a = 25^\circ C$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = -20V, I_E = 0$	—	—	-0.1	μA
Emitter Cut-off Current	I_{EBO}	$V_{EB} = -6V, I_C = 0$	—	—	-0.1	μA
Collector-Emitter Breakdown Voltage	$V(BR)_{CEO}$	$I_C = -10mA, I_B = 0$	-10	—	—	V
Emitter-Base Breakdown Voltage	$V(BR)_{EBO}$	$I_E = -1mA, I_C = 0$	-6	—	—	V
DC Current Gain	$h_{FE}(1)$ (Note 2)	$V_{CE} = -1V, I_C = -0.5A$	140	—	600	
	$h_{FE}(2)$	$V_{CE} = -1V, I_C = -4A$	60	120	—	
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = -2A, I_B = -50mA$	—	-0.2	-0.5	V
Base-Emitter Voltage	V_{BE}	$V_{CE} = -1V, I_C = -2A$	—	-0.83	-1.5	V
Transition Frequency	f_T	$V_{CE} = -1V, I_C = -0.5A$	—	140	—	MHz
Collector Output Capacitance	C_{ob}	$V_{CB} = -10V, I_E = 0, f = 1MHz$	—	50	—	pF

Note 2 : $h_{FE}(1)$ Classification Y : 140~280, GR : 200~400, BL : 300~600

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